CUSTOMER ENGINEERING TESTS FOR THE 1401 DATA PROCESSING SYSTEM

SELECT STACKER

Purpose of Test

To test the Select Stacker circuitry for both the Card Reader and the Card Punch. Detail cards punched 0, 1, or 2 in column 1 will stack in the Normal Read Stacker, Stacker 1, or Stacker 2 respectively. Blank cards passing through the Punch Feed will be punched 0, 4, or 8 in column 1 and will be stacked in the Normal Punch Stacker, Stacker 4, or Stacker 8 respectively.

Units Required

1401 Processing Unit
1402 Card Reader/Punch

Operations Used	Code
Set Word Marks	(,)
Clear	(/)
Load	(L)
Read	(1)
Move	(M)
Punch	(4)
Add	(A)
Compare	(C)
Branch	(B)
No OP	(N)
Select Stacker 1	(K1)
Select Stacker 2	(K2)
Select Stacker 4	(K4)
Select Stacker 8	(K8)

Method of Test

The complete test block consists of the following cards:

1. Title Card (0A)
2. Set Word Marks Card for Loading Routine (02)
3. Program Instruction Cards (03-42)
4. Detail Cards (43-57)

NOTE: This test can be chained but other tests cannot be chained after it.

Four Sense Switches may be brought into play as follows:

Sense Switch A ON - starts punch feed when the last card in the reader has been read.
Sense Switch B ON - permits scoping of the Select Stacker operations without card feeding as often as desired.
Sense Switch C ON - when executing the card read operations, selects all detail cards in Stacker 1; when executing the card punch operations, punches 4 in all cards fed and selects them in Stacker 4.
Sense Switch D ON - when executing the card read operations, selects all detail cards in Stacker 2; when executing the card punch operations, punches 8 in all cards fed and selects them in Stacker 8.

Normally, the test is started with Sense Switch A ON and Sense Switches B, C, and D OFF.